

Search Notes**Application/Control No.**

09/817,225

Examiner

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Applicant(s)/Patent under Reexamination

AZUMA, NOBUHIRO

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	3/06	DN
14			
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17			
26			
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
I US	3/06	DN
Patent PGPub	↓	↓
FOREIGN	↓	↓
1. EPO 2. JPO 3. Derwent	↓	↓
4. IBM-TDB	↓	↓
Reviewing Patent	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

